Se	arch	Notes	

Application	Control No.	Applicant(s)/Patent u Reexamination	nder
10/595,148		NEISE ET AL.	
Examiner		Art Unit	
Hai H. Huyr	nh	3747	

SEARCHED			
Class	Subclass	Date	Examiner
123	399	3/26/2007	ннн
123	337	3/26/2007	ннн
251	305	3/26/2007	ннн
update	search	7/2/2007	ннн
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
above	search	7/2/2007	ннн

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
East		3/26/2007	ннн
		7-2-07	ННН
		-	